For 56 years, IRPS has been the premier conference for engineers and scientists to present new and original work in the area of microelectronics reliability. Drawing participants from the United States, Europe, Asia, and all other parts of the world, IRPS seeks to understand the reliability of semiconductor devices, integrated circuits, and microelectronic assemblies through an improved understanding of both the physics of failure as well as the application environment. IRPS provides numerous opportunities for attendees to increase their knowledge and understanding of all aspects of microelectronics reliability. It is also an outstanding chance to meet and network with reliability colleagues from around the world.

**Top 3 Reasons to Attend:**

1. Listen to new and original work in the many different areas of reliability of electronic devices;

2. Increase your networking with industry leaders and professionals in the only place to have this type of exposure and training;

3. The conference is suited for a broad audience, from the reliability novice to the well-practiced engineer, including circuit and systems designers and semiconductor process experts who want to learn more about reliability.

IRPS is Co-Sponsored by IEEE EDS and Reliability Society

The 2018 IRPS conference program includes **20 tutorials** with tracks on the reliability of silicon, circuits, systems, memory, automotive and power applications; **3 focus sessions** on GaN/SiC reliability & qualification standardization, system level reliability, and 3D/2.5D/Packing reliability; **platform presentations, posters and workshops** that also include circuit aging, memory, soft errors, ESD, transistors, dielectrics, photovoltaics, and interconnects. Dr. Nirmal Saxena from NVIDIA will give a keynote titled “The Road to Resilient Computing in Autonomous Driving is Paved with Redundancy”


March 11-15, 2018
Hyatt Regency San Francisco Airport
Burlingame, CA, USA